# **Power MOSFET**

# 30 V, 35 A, Single N-Channel, SO-8 Flat Lead Package

## **Features**

- Thermally and Electrically Enhanced Packaging Compatible with Standard SO-8 Package Footprint
- New Package Provides Capability of Inspection and Probe After Board Mounting
- Ultra Low R<sub>DS(on)</sub> (at 4.5 V<sub>GS</sub>), Low Gate Resistance and Low Q<sub>G</sub>
- Optimized for Low Side Synchronous Applications
- High Speed Switching Capability

# **Applications**

- Notebook Computer Vcore Applications
- Network Applications
- DC-DC Converters

# **MAXIMUM RATINGS** ( $T_J = 25^{\circ}C$ unless otherwise noted)

Rating			Symbol	Value	Unit	
Drain-to-Source Voltage			V <sub>DSS</sub>	30	V	
Gate-to-Source Voltag	Gate-to-Source Voltage			± 20	V	
Continuous Drain	Steady	T <sub>A</sub> = 25°C	I <sub>D</sub>	22	Α	
Current (Note 1)	State	T <sub>A</sub> = 85°C		16		
	t ≤10 s	$T_A = 25^{\circ}C$		35		
Power Dissipation (Note 1)	Steady State	T <sub>A</sub> = 25°C	P <sub>D</sub>	2.4	W	
	t ≤10 s			6.25		
Continuous Drain		T <sub>A</sub> = 25°C	I <sub>D</sub>	13.5	Α	
Current (Note 2)		T <sub>A</sub> = 85°C		10		
Power Dissipation (Note 2)	Steady State	T <sub>A</sub> = 25°C	P <sub>D</sub>	0.91	W	
Power Dissipation R <sub>θJC</sub> (Note 1)		T <sub>C</sub> = 25°C	P <sub>D</sub>	100	W	
Pulsed Drain Current	ulsed Drain Current $t_p = 10 \mu s$			203	Α	
Operating Junction and Storage Temperature		T <sub>J</sub> , T <sub>stg</sub>	-55 to 150	°C		
Continuous Source Current (Body Diode)		I <sub>S</sub>	6.0	Α		
Single Pulse Drain-to-Source Avalanche Energy ( $V_{DD}$ = 30 V, $V_{GS}$ = 10 V, $I_{PK}$ = 30 A, L = 1 mH, $R_G$ = 25 $\Omega$ )			E <sub>AS</sub>	450	mJ	
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)		TL	260	°C		

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

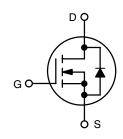
- Surface-mounted on FR4 board using 1" sq. pad size (Cu area = 1.127" sq. [1 oz] including traces).
- Surface-mounted on FR4 board using the minimum recommended pad size (Cu area = 0.412" sq.).



# ON Semiconductor®

# http://onsemi.com

V <sub>(BR)DSS</sub>	R <sub>DS(on)</sub> TYP	I <sub>D</sub> MAX
30 V	1.8 mΩ @ 10 V	35 A
30 V	2.7 mΩ @ 4.5 V	00 A







**MARKING** 

4108N = Specific Device Code A = Assembly Location

Y = Year WW = Work Week ■ = Pb-Free Package

(Note: Microdot may be in either location)

# **ORDERING INFORMATION**

Device	Package	Shipping <sup>†</sup>
NTMFS4108NT1G	SO-8 FL (Pb-Free)	1500 Tape / Reel
NTMFS4108NT3G	SO-8 FL (Pb-Free)	5000 Tape / Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

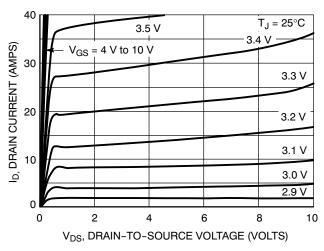
# THERMAL RESISTANCE RATINGS

Rating	Symbol	Max	Unit
Junction-to-Case (Drain)	$R_{ heta JC}$	1.25	°C/W
Junction-to-Ambient - Steady State (Note 3)	$R_{ heta JA}$	53	
Junction-to-Ambient - t ≤ 10 s (Note 3)	$R_{ heta JA}$	20	
Junction-to-Ambient - Steady State (Note 4)	$R_{\theta JA}$	138	

Characteristic	Symbol	Test Conditi	Min	Тур	Max	Unit	
OFF CHARACTERISTICS	•	•					
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		30			V
Drain-to-Source Breakdown Voltage emperature Coefficient	V <sub>(BR)DSS</sub> /T <sub>J</sub>				21		mV/°C
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>GS</sub> = 0 V, V <sub>DS</sub> = 24 V	T <sub>J</sub> = 25°C			1.0	μΑ
			T <sub>J</sub> = 125°C			25	7
Gate-to-Source Leakage Current	I <sub>GSS</sub>	V <sub>DS</sub> = 0 V, V <sub>GS</sub> = 20 V				100	nA
ON CHARACTERISTICS (Note 5)							
Gate Threshold Voltage	V <sub>GS(TH)</sub>	V <sub>GS</sub> = V <sub>DS</sub> , I <sub>D</sub> = 250 μA		1.0		2.5	V
Negative Threshold Temperature Coefficient	V <sub>GS(TH)</sub> /T <sub>J</sub>				7.5		mV/°C
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 4.5 V, I <sub>D</sub> = 19 A			2.7	3.4	mΩ
		V <sub>GS</sub> = 10 V, I <sub>D</sub> = 21 A			1.8	2.2	-
Forward Transconductance	9FS	V <sub>DS</sub> = 15 V, I <sub>D</sub> = 10 A			25		S
CHARGES, CAPACITANCES AND GATE R	ESISTANCE						
Input Capacitance	C <sub>ISS</sub>	V <sub>GS</sub> = 0 V, f = 1.0 MHz, V <sub>DS</sub> = 15 V			6000		pF
Output Capacitance	C <sub>OSS</sub>				1200		
Reverse Transfer Capacitance	C <sub>RSS</sub>				700		
Total Gate Charge	Q <sub>G(TOT)</sub>	V <sub>GS</sub> = 4.5 V, V <sub>DS</sub> = 24 V, I <sub>D</sub> = 21 A			54		nC
Threshold Gate Charge	Q <sub>G(TH)</sub>				11		
Gate-to-Source Charge	$Q_{GS}$				16		
Gate-to-Drain Charge	$Q_{GD}$				23		
Gate Resistance	$R_{G}$				0.7		Ω
SWITCHING CHARACTERISTICS, $V_{GS} = 10$	<b>V</b> (Note 6)						
Turn-On Delay Time	t <sub>d(ON)</sub>				45		ns
Rise Time	t <sub>r</sub>	V <sub>GS</sub> = 4.5 V, V <sub>DS</sub> :	= 15 V,		60		
Turn-Off Delay Time	t <sub>d(OFF)</sub>	$I_D = 1.0 \text{ A}, R_G = 6.0 \Omega$			70		
Fall Time	t <sub>f</sub>				140		
DRAIN-SOURCE DIODE CHARACTERISTI	cs						
Forward Diode Voltage	V <sub>SD</sub>	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 6.0 A	T <sub>J</sub> = 25°C		0.72	1.1	V
			T <sub>J</sub> = 125°C		0.65		1
Reverse Recovery Time	t <sub>RR</sub>	$V_{GS} = 0 \text{ V}, d_{1S}/d_t = 100 \text{ A/}\mu\text{s},$ $I_S = 6.0 \text{ A}$			41		ns
Charge Time	t <sub>a</sub>				20		
Discharge Time	t <sub>b</sub>				21		
Reverse Recovery Charge	$Q_{RR}$				45		nC

- Surface-mounted on FR4 board using 1" sq. pad size (Cu area = 1.127" sq. [1 oz] including traces).
   Surface-mounted on FR4 board using the minimum recommended pad size (Cu area = 0.412" sq.).
   Pulse Test: Pulse Width ≤ 300 μs, Duty Cycle ≤ 2%.
   Switching characteristics are independent of operating junction temperatures.

# TYPICAL PERFORMANCE CURVES



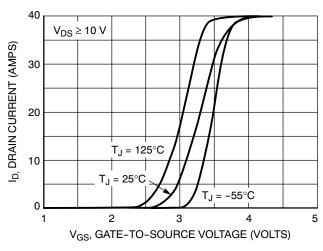


Figure 1. On-Region Characteristics

Figure 2. Transfer Characteristics

 $T_J = 25^{\circ}C$ 

25

30

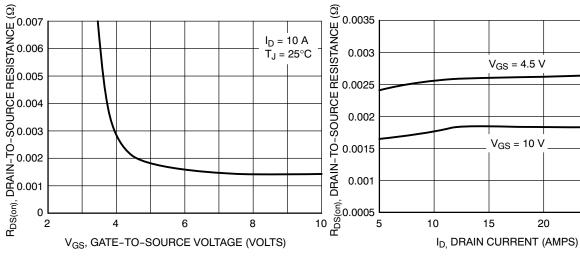


Figure 3. On-Resistance vs. Gate-to-Source Voltage

Figure 4. On-Resistance vs. Drain Current and Gate Voltage

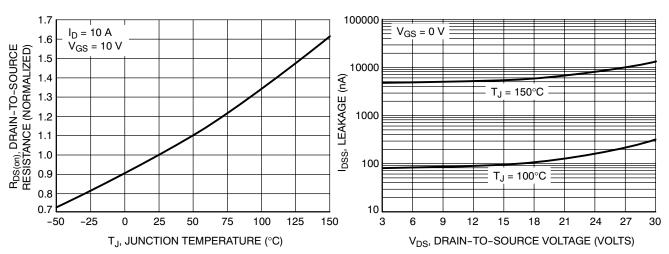


Figure 5. On–Resistance Variation with Temperature

Figure 6. Drain-to-Source Leakage Current vs. Voltage

# **TYPICAL PERFORMANCE CURVES**

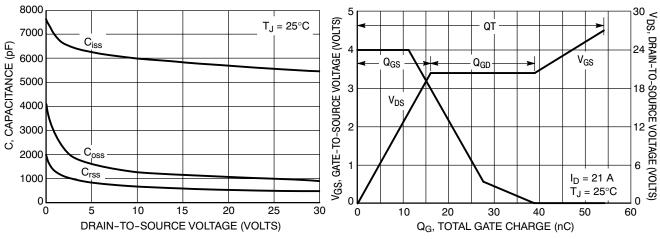


Figure 7. Capacitance Variation

Figure 8. Gate-To-Source and Drain-To-Source Voltage vs. Total Charge

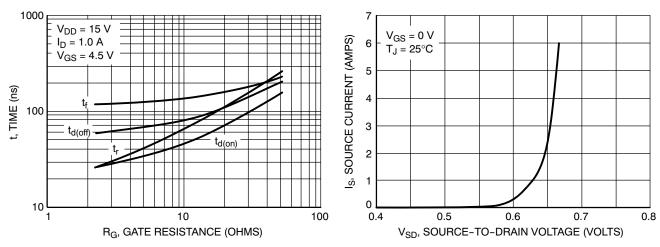


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

Figure 10. Diode Forward Voltage vs. Current

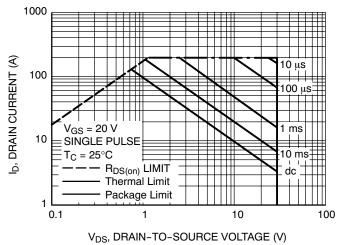
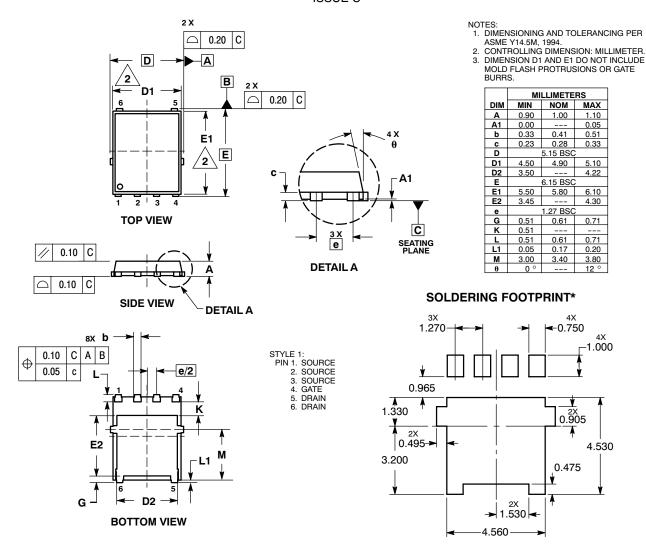


Figure 11. Maximum Rated Forward Biased Safe Operating Area

### PACKAGE DIMENSIONS

# DFN6 5x6, 1.27P (SO8 FL) CASE 488AA-01 ISSUE C



\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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